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Pages:626

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Pages:94 - 99

[\[Abstract\]](#) [\[PDF Full-Text \(568 KB\)\]](#) IEEE CNF
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Pages:131 - 135

[\[Abstract\]](#) [\[PDF Full-Text \(424 KB\)\]](#) IEEE CNF

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Pages:268 - 277

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Pages:1047 - 1056

[\[Abstract\]](#) [\[PDF Full-Text \(1004 KB\)\]](#) IEEE CNF

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Pages:1057 - 1064

[\[Abstract\]](#) [\[PDF Full-Text \(556 KB\)\]](#) IEEE CNF

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Pages:323 - 330

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Pages:179 - 187

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Pages:421 - 425

[\[Abstract\]](#) [\[PDF Full-Text \(524 KB\)\]](#) IEE JNL**14 Design of compactors for signature-analyzers in built-in self-test***Wohl, P.; Waicukauski, J.A.; Williams, T.W.;*

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Pages:54 - 63

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